

Search Notes**Application/Control No.**

10/696,203

Examiner

Sun J. Lin

Applicant(s)/Patent under Reexamination

HANSON ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	19	1/5/2006	JSL
716	21	1/5/2006	JSL
716	4	1/5/2006	JSL
716	2	1/5/2006	JSL
716	1	1/5/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	1/5/2006	JSL
IEEE	1/5/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner